



Superior Magnetics Since 1979



CMOQ-1

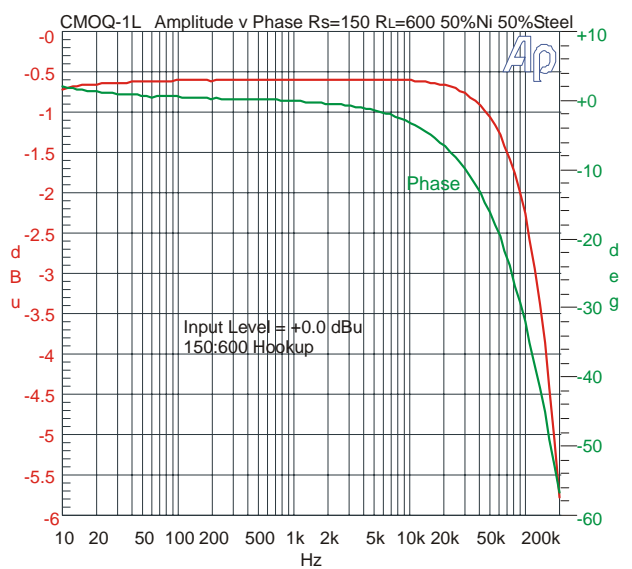
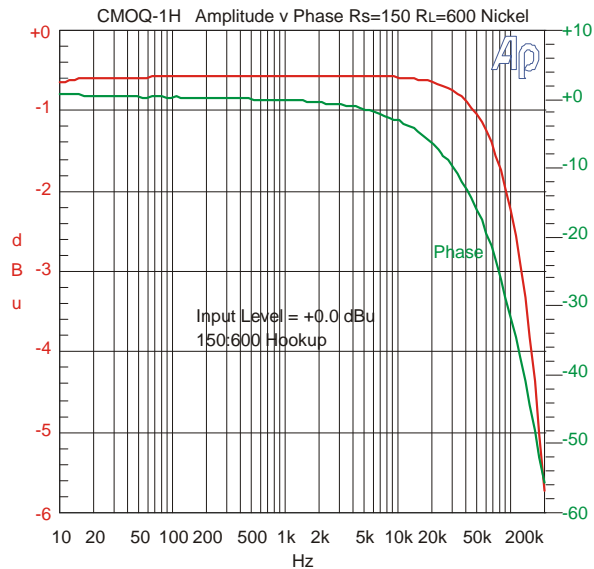
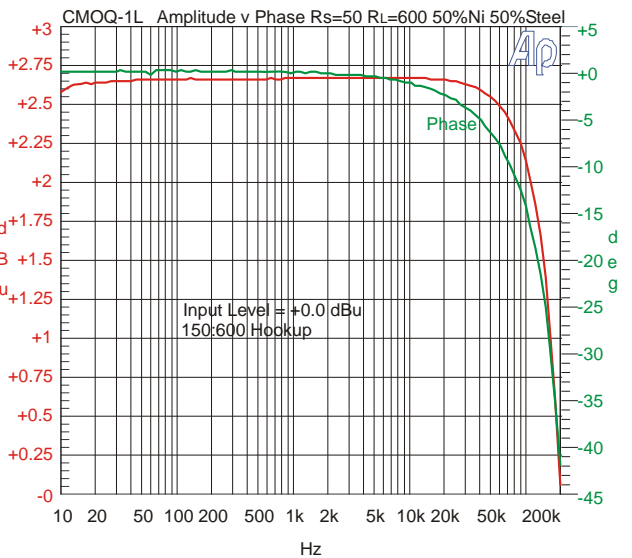
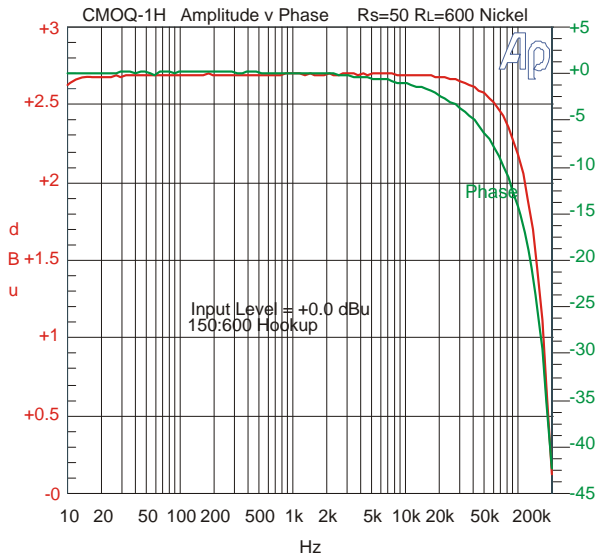
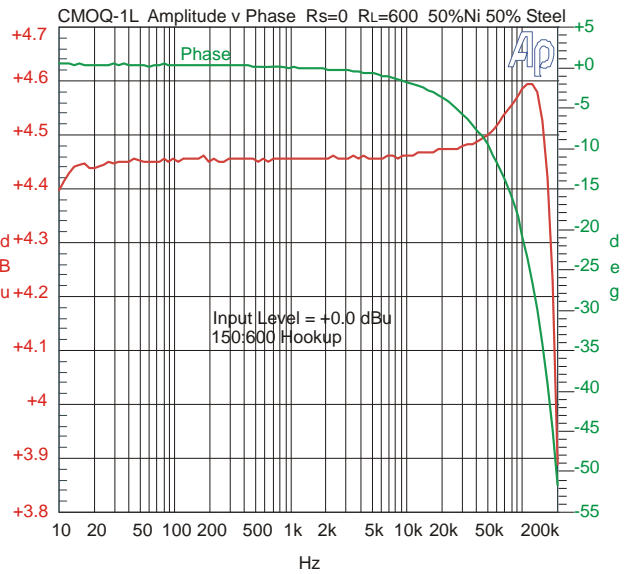
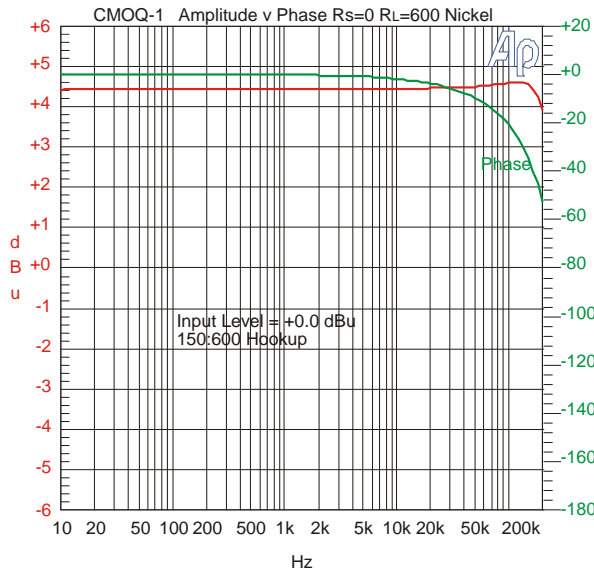
LINE OUTPUT TRANSFORMER Quadfilar Windings

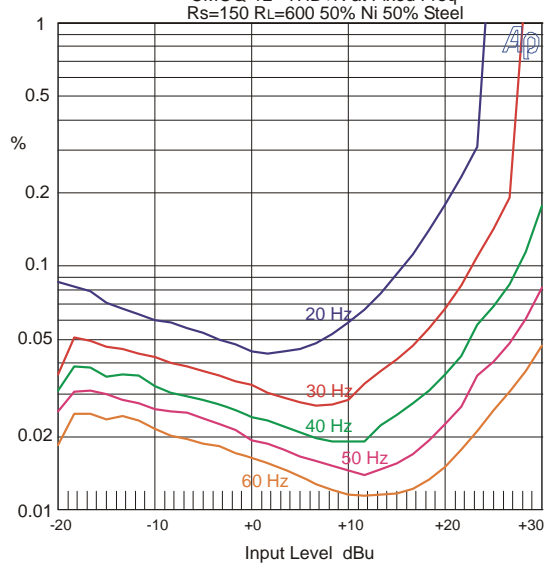
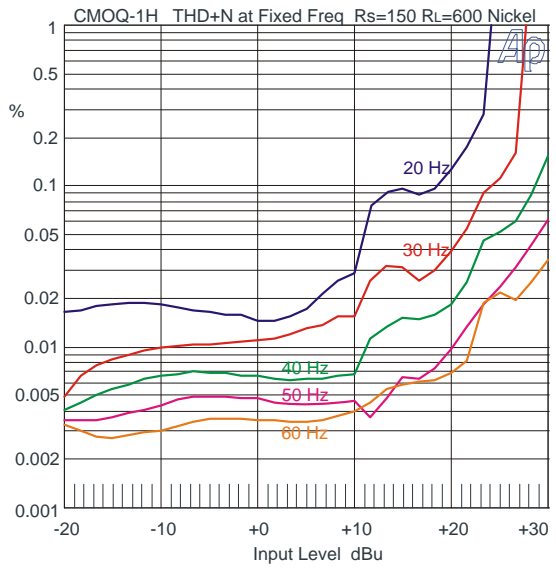
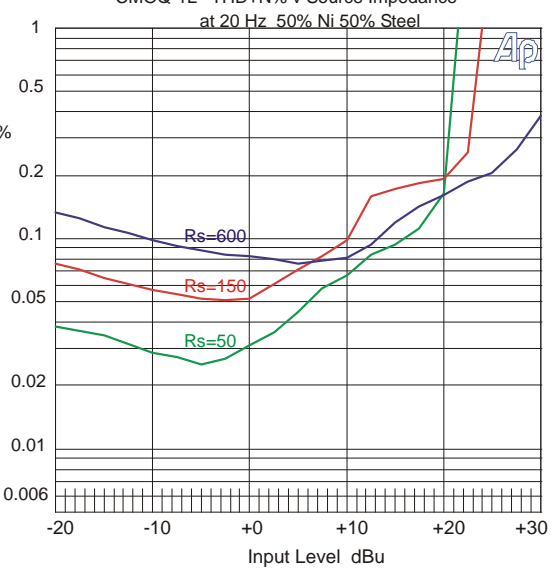
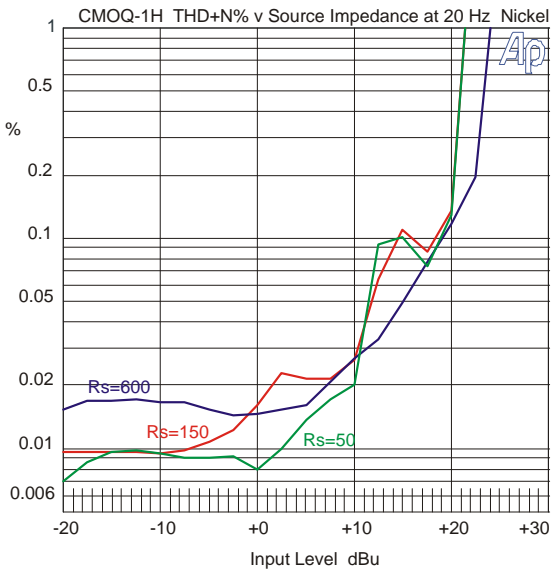
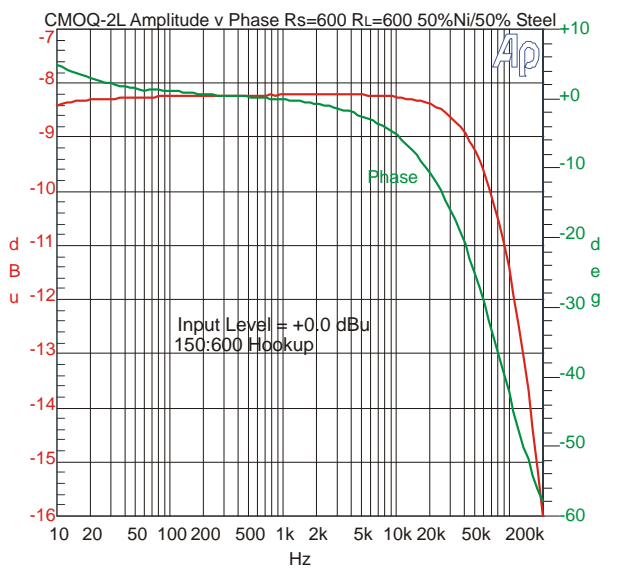
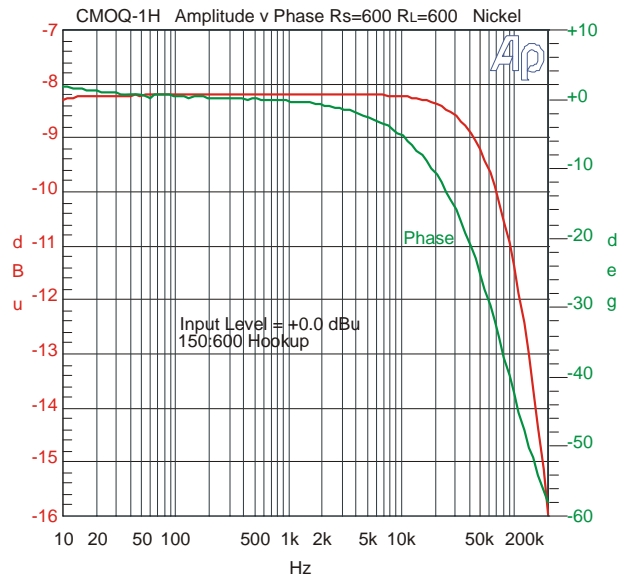
- Excellent bandwidth: -3 dB at 150 kHz
- {Rs=150Ω 80% Nickel (“HiNi”) laminations}
- Distortion 0.02% typ at 20 Hz, Rs=150Ω HiNi
- +24 dBm at 20 Hz, 1% THD+N Rs≤150Ω
- Phase Shift -6° at 20 kHz, Rs=150Ω
- Low insertion loss

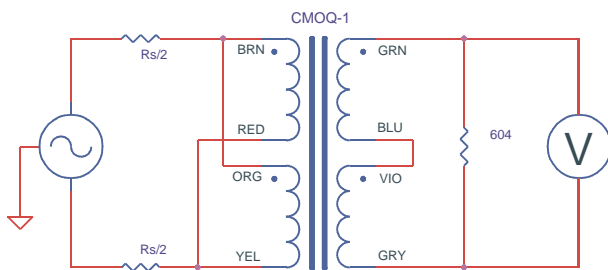
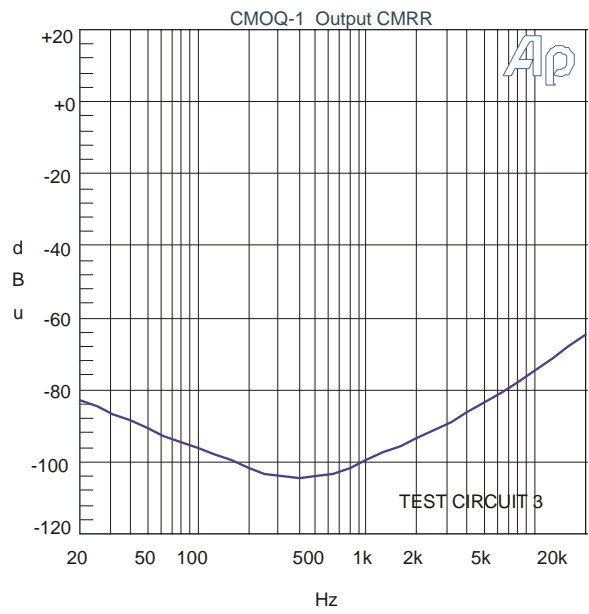
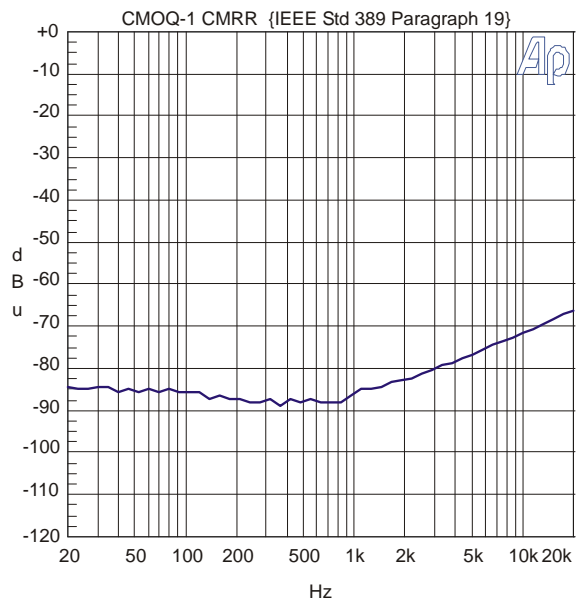
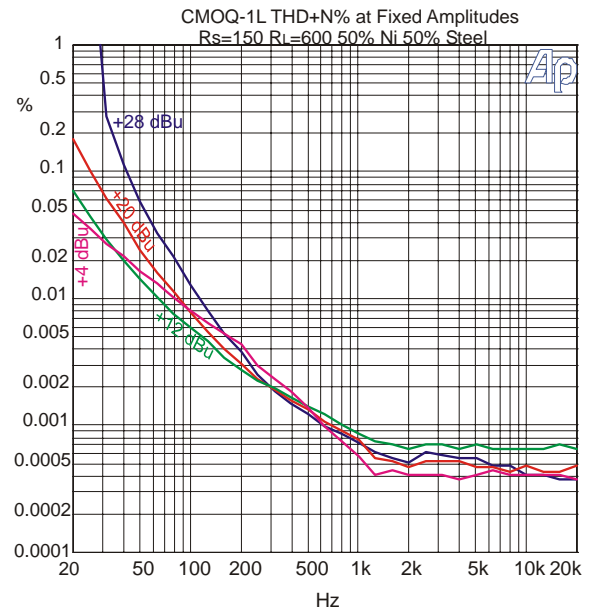
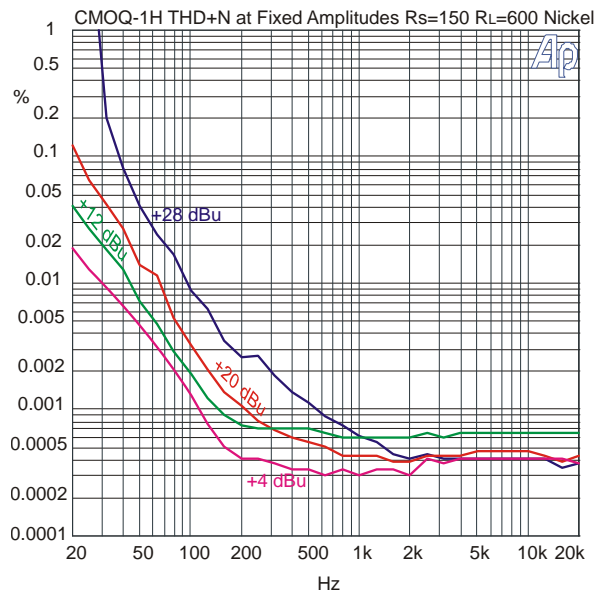
The CineMag CMOQ-1 output transformer uses quadfilar construction techniques. This four-winding transformer delivers good coupling between windings as well as excellent bandwidth. It is available both with 80% Nickel (“HiNi”) and 50% Nickel/50% Steel laminations. It can be driven with source impedances of up to 600Ω. As with all line driving devices, the amplifier feeding it must be capable of cleanly delivering the power required to reach maximum operating level. See AN-102.

CMOQ-1H / CMOQ-1L

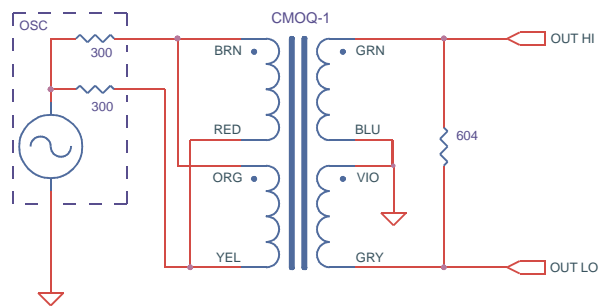
Parameter	Conditions	Typ
Turns Ratio		1 : 1.00
Input Impedance, Zi	20 Hz to 20 kHz, +0 dBu Test Circuit 4	620Ω
Voltage Gain	1 kHz HiNi Core, 150Ω:600Ω Rs=0 1 kHz 50% Nickel/50% Steel Core, Rs=0	+4.45 dB +4.45 dB
Distortion (THD+N%)	1 kHz, +4 dBu, Rs=150 HiNi Test Circuit 1 1 kHz, +4 dBu, Rs=150 50%Ni/50% Steel	0.0003% 0.0006%
Max 20 Hz input level	1.0% THD+N, Rs≤150 HiNi Test Circuit 1 1.0% THD+N, Rs≤150 50% Ni 50% Steel	+24 dB +24 dB
Response, ref 1 kHz	20 Hz Rs=150Ω HiNi Test Circuit 1 20 kHz Rs=150Ω HiNi Test Circuit 1 -3dBu Rs=150Ω HiNi Test Circuit 1	-0.01 dB -0.01 dB 150 kHz
Phase Shift at 20Hz Phase Shift at 20 kHz	Referenced to source generator Test Circuit 1	+0.1° -6°
CMRR	60 Hz Test Circuit 2 per IEEE Std 389-1996 ¶19 1 kHz Test Circuit 2 per IEEE Std 389-1996 ¶19	85 dB 84dB
Output CMRR	60 Hz Test Circuit 3 1 kHz Test Circuit 3	85 dB 85 dB
Operating Temp Range	Operation and storage	0° C Min 70° C Max



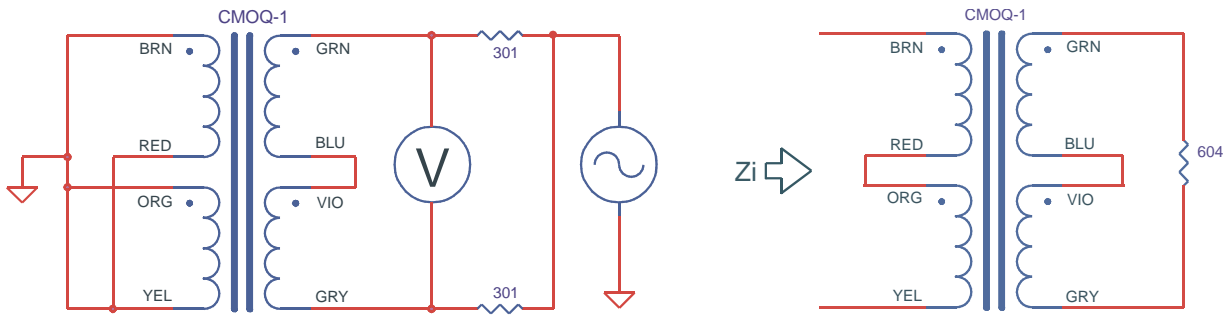




TEST CIRCUIT 1



TEST CIRCUIT 2



TEST CIRCUIT 3

TEST CIRCUIT 4

NOTES:

1. All graphs generated from one (1) randomly chosen device. No statistical averaging or weighting. Data from one sweep.
2. $R_L = 604$ unless otherwise noted.

